

RELIABILITY DATA

LT1128

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF FAILURES ⁽²⁾
CERDIP	44	9213	9213	44.11	0
PLASTIC DIP	44	9213	9213	21.93	0
SOIC/SOT/MSOP	47	9524	9524	44.22	0
	135			110.25	0

• HIGHLY ACCELERATED STRESS TEST AT +131°C/85%RH

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽⁴⁾ AT +85°C	NUMBER OF FAILURES
SOIC/SOT/MSOP	100	0038	0217	96.00	0
	100			96.00	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	48	9450	9450	1.15	0
SOIC/SOT/MSOP	8,671	9337	0044	439.49	0
DD PACK	2,150	9404	9801	51.60	0
TO-220	650	9448	9636	15.60	0
	11,519			507.84	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	100	9450	0045	10.00	0
SOIC/SOT/MSOP	225	9437	0044	22.50	0
	325			32.50	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	100	9437	0044	10.00	0
	100			10.00	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 16.68 FITS

(3) Mean Time Between Failures in Years = 6,839

(4) Assumes 20X Acceleration from 85°C to +131°C

Note: 1 FIT = 1 Failure in One Billion Hours.